Introduction to Focused Particle Beam Technology
Abbreviated* Application Training Syllabus.

1. Introduction;
2. Sources for focused electron beams;
3. Electron beam optics;
4. Electron beam to sample interaction, sample charging;
5. Secondary signals, image formation and contrast mechanisms;
6. Sources for focused ion beams;
7. Ion optics;
8. Ion beam to sample interactions, sample charging;
9. Secondary signals, image formation and contrast mechanisms;
10. Precursor gases for Ion and E-beam chemistries;
11. Ion beam induced etching and deposition;
12. E-beam induced etching and deposition;
13. Comparison of E-beam and Ion beam induced processes;

*Detailed syllabus is available upon request sent to: info@partbeamsystech.com